

Applicant:	Kyocera
FCC ID:	V65SCP-8600
Report #:	CT-8600-20RF-0510-R1

Hearing Aid Compatibility (HAC) RF Emissions

FCC 47 CFR Part 20.19

Test Report

For

Kyocera Corporation c/o Kyocera Communication Inc.

Product:	Dual-Band CDMA Phone	
Model:	SCP-8600	



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ATTESTATION

The tested device complies with the requirements in respect of all parameters subject to the test. The test results and statements relate only to the items tested.

The test equipment used was suitable for the tests performed and within manufacturer's published specifications and operating parameters.

The test methods were consistent with the methods described in the relevant standards.

Product:	Dual-Band CDMA Cellular Phone with Bluetooth and WLAN	
Model #:	SCP-8600	
FCC ID:	V65SCP-8600	
Tested in accordance with:	FCC 47 CFR Part 20.19	
	ANSI C63.19-2007	
Test performed by: Comptest Services LLC		
Test Requested by:	KYOCERA Corporation	
C/o KYOCERA Communication Inc		
	10300 Campus Point Drive	
	San Diego, CA 92121 United States	
Date of Test:	May 11, 2010	

Responsible Engineer	Reviewed and approved by:	
Benjamin Nguyen	ammyb	
Benjamin Nguyen	Tammy To	
Test Engineer	Quality Manager	



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SUMMARY OF TESTING

Rule Part	Test Description	Section #	Verdict
FCC § 20.19(b), §6.3(v), §7.3(v)	HAC RF Emissions	4	Pass
ANSI C63.19-2007 HAC M Category:			M4

2 EQUIPMENT UNDER TEST INFORMATION

Product:	Dual-Band CDMA Cellular Phone with Bluetooth and WLAN		
FCC ID:	V65SCP-8600		
Model Number:	SCP-8600		
EUT Serial Number:	A0000012FEED3F		
Type:	[] Identical Prototype,		
	[X] Pre-Production,		
	[] Production		
Device Category:	Portable		
RF Exposure Environment:	General Population / Uncontrolled		
Antenna:	Internal		
Detachable Antenna:	Yes		
External Input:	Audio/Digital Data	Audio/Digital Data	
Quantity:	Quantity production is planned		
Modes:	800 CDMA	1900 CDMA	
Multiple Access Scheme:	CDMA	CDMA	
TX Frequency (MHz):	824 – 849 1850 - 1910		
Rated RF Conducted Output Power (dBm)	24.0		



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3 TEST CONDITIONS

3.1 Ambient Conditions	
All tests were performed under the followin	g environmental conditions:
Ambient Temperature:	23 ± 2 Degrees C
Tissue simulating liquid temperature:	22 ± 1 Degrees C
Relative Humidity (RH):	0% <rh 80%<="" <="" td=""></rh>
Atmospheric Pressure:	101.3kPa + 10 to -5 kPa

3.2 RF characteristics of the test site

All HAC measurements were performed inside a shielded room that provide isolation from external EM fields, with the RF ambient at least 20 dB below the intended measurement limits.

3.3 Test Signal, Frequencies and Output Power

The device supports CDMA2000 in 1X (Phase I, Protocol revision 6) mode only. CDMA2000 1X includes TIA/EIA-95B as a subset and was approved for publishing in July 1999. It provides voice and data capabilities within a standard 1.25 MHz CDMA channel. This RF bandwidth is identical to the legacy IS-95 B system standard.

Peak and Average conducted power were measured to ensure worst case power configuration was tested:

CONFIGURATION		CONDUCTED POWER	
(Full Rate)		CDMA 800	CDMA 1900
,		(ch 383)	(ch 600)
		Average (dBm)	Average (dBm)
SO2	RC1	24.00	23.72
	RC3	24.03	23.81
SO55	RC1	24.01	23.80
	RC3	24.04	23.82
SO32	RC3 (+F-SCH)	23.93	23.79
	RC3 (+SCH)	23.91	23.75

In all operating modes, the phone was set to rated maximum RF power level and the measurements were performed on low, mid and high channels.

The measurement system measures power drift during HAC testing by comparing E/H-field in the same location at the beginning and at the end of measurement. These records were used to monitor stability of power output during tests. Conducted RF power measurements were also performed before and after each HAC measurements to confirm the output power.



During tests, the EUT was put in in-call mode and controlled by a CDMA simulator to generate the required signal and power:			
Protocol:	6 (IS-2000)		
Radio Configuration:	3		
Power Control:	All Up Bits		
Service Option:	55		
Data Rate:	Full		

3.4	EUT Operating Conditions
The	EUT was tested with the follow configurations and conditions, if applicable:
X	Fully charged standard battery as supplied with the handset Closed configurations at ear use position ¹ Both retracted and extended antenna positions Back-light always ON Simultaneous transmission with Bluetooth transmitter ON ²
	e: *The Bluetooth transmitter was not enable during tests, since the intended use of the CDMA smitter does not include support simultaneous operation when held to ear.



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4 DESCRIPTION OF TEST EQUIPMENT

4.1 Test Equipment Used

Below is a list of the calibrated equipment used for the measurements.

The calibration certificates of E-field and H-field probes are attached in Appendix A.

Description	Manufacturer	Model Number	Serial Number	Cal Due Date
Power Meter	Giga-tronics	8541C	1831306	07/16/10
Signal Generator	Hewlett Packard	E4421B	US38440337	07/14/10
Radio Communication Tester	Agilent	8960	GB44052789	08/13/10
Data Acquisition	Speag	DAE4	602	06/17/10
E-field Probe	Speag	ER3DV6	2282	08/14/10
H-field Probe	Speag	H3DV5	6123	07/16/10
Dipole Antenna (835MHz)	Speag	CD835V3	1020	04/26/11
Dipole Antenna (1880MHz)	Speag	CD1880V3	1015	04/26/11

Note: Dipoles are calibrated on a 2-year interval. Dipoles return-loss and input impedances are measured annually (50824 DO2 Dipole SAR Validation Verification v01).

4.2 Near Field Measurement System

The measurements were performed with Dasy4 automated near-field scanning system comprised of high precision robot, robot controller, computer, near-field probe, probe alignment sensor, non-conductive phone positioner, Test Arch and software extension. The overall expanded uncertainty (K=2) of the measurement system is $\pm 10.9\%$ and $\pm 14.7\%$ for H-field and E-field resp. The measurement uncertainty budget is given in section 6.



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4.3 Isotropic E-	Field Probe
Model	■ ER3DV6
Construction	One dipole parallel, two dipoles normal to probe axis
	Built-in shielding against static charges
	 PEEK enclosure material (resistant to organic solvents, e.g., glycolether)
Calibration	■ In air from 100 MHz to 3.0 GHz (absolute accuracy ± 6%; k=2)
Frequency	■ 100MHz to 6 GHz
	■ Linearity: ± 0.2dB (100MHz to 3GHz)
Directivity	 ± 0.2 dB in air (rotation around probe axis)
	■ ± 0.4 dB in air (rotation normal to probe axis)
Dynamic Range	■ 2 V/m to > 1000 V/m
	■ Linearity: ± 0.2 dB
Dimensions	Overall length: 330 mm (Tip: 16 mm)
	■ Tip diameter: 8 mm (Body: 12 mm)
	 Distance from probe tip to dipole centers: 2.5 mm
Application	 General near-field measurements up to 6 GHz
	Field component measurements
	Fast automatic scanning in phantoms

4.4 Isotropic -Field	Probe
Model	■ H3DV6
Construction	 Three concentric loop sensors with 3.8 mm loop diameters
	 Resistively loaded detector diodes for linear response
	Built-in shielding against static charges
	 PEEK enclosure material (resistant to organic solvents, e.g., glycolether)
Frequency	■ 200 MHz to 3 GHz (± 6.0%, k=2); Output linearized
Directivity	■ ± 0.25 dB (spherical isotropy error)
Dynamic Range	■ 10 mA/m to 2 A/m at 1 GHz
E-Field Interference	< 10% at 3 GHz (for plane wave)
Dimensions	Overall length: 330 mm (Tip: 40 mm)
	■ Tip diameter: 6 mm (Body: 12 mm)
	 Distance from probe tip to dipole centers: 3 mm
Application	 General magnetic near-field measurements up to 3 GHz
	■ Field component measurements
	 Surface current measurements
	 Measurements in air or liquids
	Low interaction with the measured field

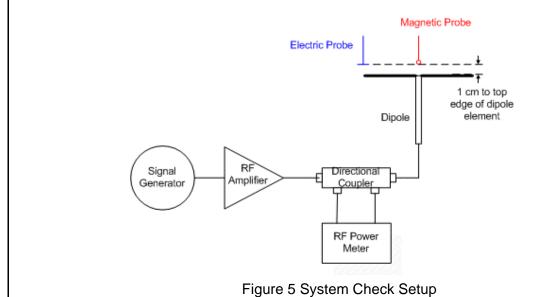


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SYSTEM VALIDATION

5.1 Dipole Validation Setup

The probes are calibrated annually by the manufacturer. The HAC measurements of the device were done within 24 hours of system accuracy verification, which was done using calibration dipoles. Unmodulated continous wave of power level of 20dBm was supplied to a dipole antenna placed under Test Arch. The measurement probes are positioned over the illuminated dipole at 10mm distance from the top surface of the dipole element to the calibration reference point of the sensor, defined by the probe manufacturer.





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5.2 Dipole Validation Results

The length of the dipole was scanned with both E and H-field probes and the maximum values for each were recorded. The validation results are in the table below and printouts of the validation test are attached in Appendix B. All the measured parameters were within the specification.

Freq. (MHz)	Parameter	Target (SPEAG)	Measured	Delta (%)	Limit (%)	Test date
835	E dB(V/m)	159.5	160.1	0.38	± 25	05-11-10
	H dB(A/m)	0.458	0.459	0.20	± 25	05-11-10
1880	E dB(V/m)	140.4	137.5	-2.07	± 25	05-11-10
	H dB(A/m)	0.466	0.476	2.06	± 25	05-11-10



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DESCRIPTION OF TEST PROCEDURE

6.1 Test Positions

The device was placed on a non-conductive phone positioner under the Test Arch.

6.2 RF Emission Measurements Reference and Plane

Figure 6.2 illustrates the references and reference plane that shall be used in the EUT emissions measurement:

- The grid is 5 cm by 5 cm area that is divided into 9 evenly sized blocks or sub-grids.
- The grid is centered on the audio frequency output transducer (speaker) of the EUT.
- The grid is in a reference plane, which is defined as the planar area that contains the highest point in the area of the phone that normally rests against the user's ear. It is parallel to the centerline of the receiver of the EUT and is defined by the points of the receiver-end of the EUT, which, in normal handset use, rest against the ear.
- The measurement plane is parallel to, and 1.5 cm in front of, the reference plane.

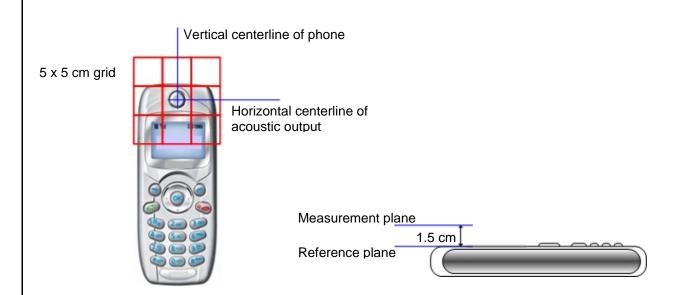


Figure 6.2 – Measurement Reference and Plane



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6.3 RF Emissions Measurement Procedures

Flowchart below shows the near field emission measurement:

- 1. The center of the probe was scan to the edges of the grid. Accordingly the total area covered by the outside edge of the probe was the 5 cm by 5 cm area, increased by half (½) the probe diameter on all sides.
- 2. The nearest point on the probe measurement element(s) was held 1.0 cm from the EUT reference plane.
- 3. The probe element is that portion of the probe that is designed to receive and sense the field being measured.
- 4. The physical body of the probe housing was not used when setting this 1.0 cm distance as this would place the sensing elements at an indeterminate distance from the reference plane.
- 5. The step size of the scan is set to 5 mm or less.
- 6. Up to three blocks were excluded for each field measurement.
 - The center block containing the EUT output was not excluded.
 - A maximum of five blocks were excluded for both E- and H-field measurements for the EUT output being measured. Stated differently, the center sub-grid or block and 3 other blocks were common to both the E- and H-field measurements for a given grid.

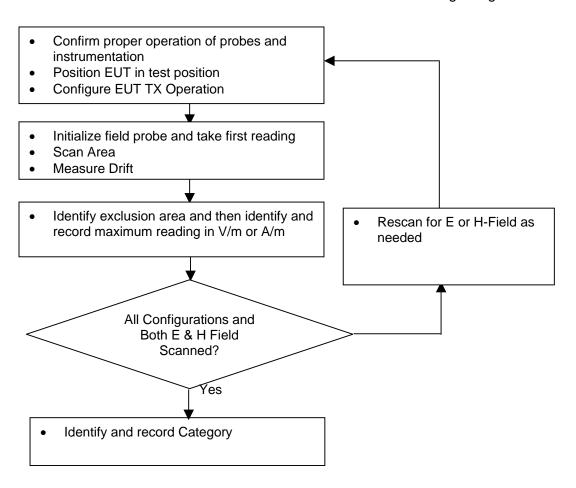


Figure 7.6 Near field emission measurement flowchart



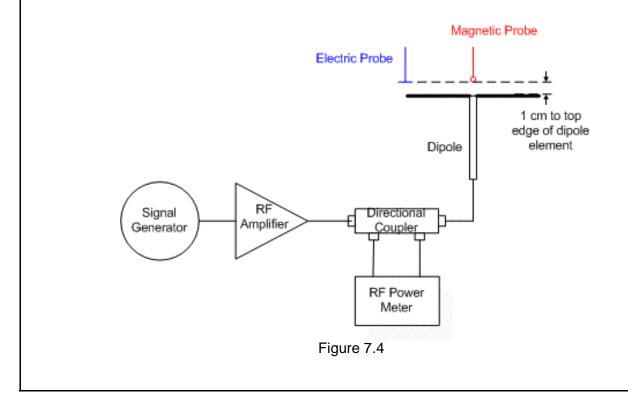
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PROBE MODULATION FACTOR (PMF)

7.1 PMF Measurement Procedures

A calibration was made of the modulation response of the probe and its instrumentation chain. This calibration was performed with the field probe, attached to its instrumentation. The response of the probe system to a CW field at the frequency of interest is compared to its response to a modulated signal with equal peak amplitude to that of a CW signal. The field level of the test signals shall be more than 10 dB above the ambient level and the noise floor of the instrumentation being used. The ratio of the CW reading to that taken with a modulated reading was applied to the DUT measurements. The measurement procedures are as following:

- 1. Fix the field probe in a set location relative to the dipole antenna, as illustrated in Figure 7.4.
- 2. Setup the wireless device (EUT) with intended signal at the intended measurement frequency.\
- 3. Record the reading of the probe measurement system.
- 4. Replace the wireless device with a RF signal generator producing an unmodulated CW signal and set to the wireless device operating frequency.
- 5. Set the peak power of the unmodulated signal to equal that recorded from the wireless device
- 6. Record the reading of the probe measurement system of the unmodulated CW signal.
- 7. The ratio of probe reading (CW) in step 6 to the probe reading (EUT) in step 3 is the modulation factor.





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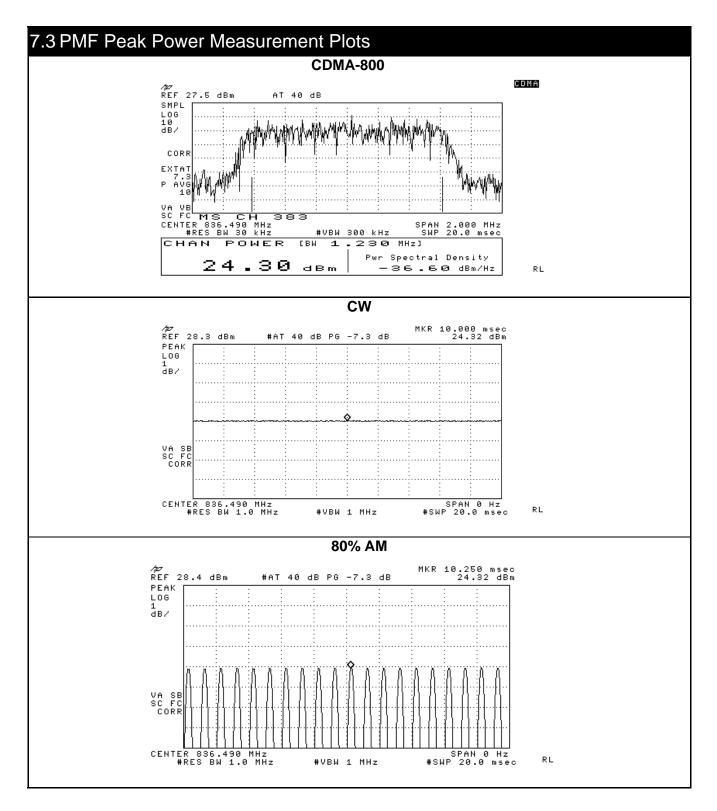
7.2 PMF Test Results

The modulation factors obtained by above method shall be applied to readings taken of the actual WD, in order to obtain an accurate peak field reading.

WD, in order to obtain an accurate peak field reading. E-Field							
Frequency Peak Power (MHz) (dBm)		Protocol	Protocol Reading (V/m)	Modulation Factor			
835	24.32	CW	127.6				
	24.3	CDMA (full rate)	127.4	1.00			
	24.32	AM	77.77	1.64			
1880	22.92	CW	69.51				
	22.92	CDMA (full rate)	70.66	0.98			
22.92		AM	44.42	1.56			
		H-Field					
Frequency (MHz)	Peak Power (dBm)	Protocol	Protocol Reading (A/m)	Modulation Factor			
835	24.5	CVA					
	24.5	CW	0.343				
	24.5	CDMA (full rate)	0.343 0.335	1.02			
				1.02 1.54			
1880	24.5	CDMA (full rate)	0.335				
	24.5 24.61	CDMA (full rate) AM	0.335 0.223				



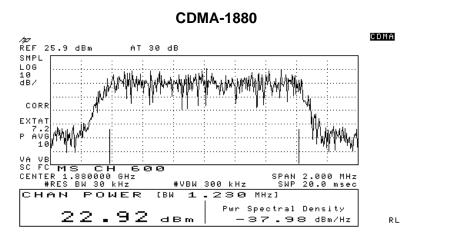
Applicant:	Kyocera
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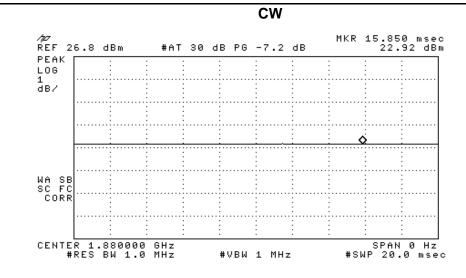


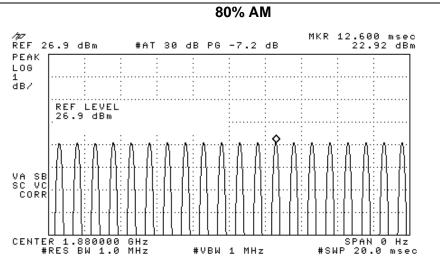


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8 EMISSION DATA EXTRACTION AND POSTPROCESSING

At the end of the measurements, the DASY4 system automatically evaluates the slot-averaged results, exclusion of the three highest subgrid, application of the AWF factor per ANSI-C63.19 requirements.

The following AWF factors were used for the standard transmission protocols:

Standard	Technology	AWF
TIA/EIA/IS-2000	CDMA	0
TIA/EIA-136	TDMA (50 Hz)	0
J-STD-007	GSM (217)	-5
T1/T1P1/3GPP	UMTS (WCDMA)	0
iDEN™	TDMA(22 and 11 Hz)	0

Table 8.1 Articulation Weighting Factor (AWF)

All DASY4 measurements are in RMS values. The Dasy4 system incorporates the crest factor of the signal in the computation of the RMS values. Although the software also has the capability to estimate the peak field by applying a square root of the crest factor value to the readings, the probe modulation factor was applied manually instead per ANSI C63.19 in the measurement tables in this report using equation:

Peak Field = (DASY4 reading) x PMF

where DASY4 reading = measurement from DASY4 in V/m or A/m PMF = Probe Modulation Factor in linear unit



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MEASUREMENT UNCERTAINTY

Table 8.1 shows the uncertainty budget for HAC free field assessment according to ANSI C63.19-2007. The budget is valid for the frequency range 800 MHz - 3 GHz and represents a worst-case analysis. For specific tests and configurations, the uncertainty could be smaller.

Uncertainty Description	Uncert . Value (± %)	Prob Dist.	Div.	C _i (E)	C _i (H)	Stand. Uncert (E) (±%)	Stand. Uncert (H) (±%)
Measurement system		•			•	, ,	, ,
Probe calibration	5.1	N	1	1	1	5.1	5.1
Axial isotropy of the probe	4.7	R	√3	1	1	2.7	2.7
Sensor displacement	16.5	R	√3	1	0.14	9.5	1.4
Poundary offects	2.4	R	√3	1	5 1	1.4	1.4
Boundary effects Probe linearity	4.7	R	√3	1	1	2.7	2.7
Scaling to Peak Envelope	2.0	R	$\sqrt{3}$	1	1	1.2	1.2
Power	2.0	K		-	1	1.2	1.2
System Detection limit	1.0	R	√3	1	1	0.6	0.6
Readout electronics	0.3	N	1	1	1	0.3	0.3
Response time	0.8	R	√3	1	1	0.5	0.5
Integration time	2.6	R	√3	1	1	1.5	1.5
RF ambient conditions	3.0	R	√3	1	1	1.7	1.7
RF Reflections	12	R	√3	1	1	6.9	6.9
Probe Positioner	1.2	R	√3	1	0.67	0.7	0.5
Probe positioning	4.7	R	√3	1	0.67	2.7	1.8
Extrap. and integration	1.0	R	√3	1	1	0.6	0.6
Test Sample Related							
Device positioning vertical	4.7	R	√3	1	0.67	2.7	1.8
Device Positioning Lateral	1.0	R	√3	1	1	0.6	0.6
Device Holder and Phantom	2.4	R	√3	1	1	1.4	1.4
Power drift	5.0	R	√3	1	1	2.9	2.9
Phantom and Setup Related							
Phantom thickness	2.4	R	√3	1	0.67	1.4	0.9
	Comb	ined St	andard	Uncer	tainty:	14.7	10.9
Extended Standard Uncertainty on Power (k=2):						29.4	21.8
Extended Standard Uncertainty on Field (k=2):						14.7	10.9

N: Normal R: Rectangular

Table 9.1 Worst-Case uncertainty budget for HAC free field assessment



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10 RF EMISSIONS TESTS

10.1 Emission Limits

FCC: § 20.19, ANSI C63.19-2007

IC:

Table 10.1 shows the M-rating criteria from ANSCI C63.19. All digital transmission modes in all frequency bands contained in a HAC phone must meet M3 or M4 levels.

Near Field	Wireless Device RF Parameters [AWF = 0]						
Cotogory	E-Field E	missions	H-Field Emissions				
Category	dB(V/m) Peak V/m Peak		dB(A/m) Peak	A/m Peak			
		Freq < 960 M	Hz				
M1	56.0 to 61.0	631.0 to 1122.0	5.6 to 10.6	1.91 to 3.39			
M2	51.0 to 56.0	354.8 to 631.0	0.6 to 5.6	1.07 to 1.91			
М3	46.0 to 51.0	199.5 to 354.8 -4.4 to 0.6		0.60 to 1.07			
M4	< 46.0	< 199.5 < -4.4		< 0.60			
		Freq > 960 M	Hz				
M1	46.0 to 51.0	199.5 to 354.8	-4.4 to 0.6	0.60 to 1.07			
M2	41.0 to 46.0	112.2 to 199.5	-9.4 to -4.4	0.34 to 0.60			
M3	36.0 to 41.0	63.1 to 112.2	-14.4 to -9.4	0.19 to 0.34			
M4	< 36.0	< 63.1	< -14.4	< 0.19			

Table 10.1 RF Emission Limits



10.2 CDMA 800 Test Results						
Configuration: Standard Battery Antenna: Fixed						
	CDMA 800 E-Field					
Ch.	Backlight	Power	Dasy4 Reading	PMF	Peak Field	Category
#		dBm	V/m		V/m	M
1013	ON	23.88	70.6	1.00	70.6	4
383	ON	24.04	88.7	1.00	88.7	4
777	ON	23.95	79.1	1.00	79.1	4
		CI	DMA 800 H-Fie	eld		
Ch.	Backlight	Power	Dasy4 Reading	PMF	Peak Field	Category
#		dBm	A/m		A/m	M
1013	ON	23.88	0.138	1.00	0.138	4
384	ON	24.04	0.113	1.00	0.113	4
777	ON	23.95	0.104	1.00	0.104	4



10.3 CDMA 1900 Test Results							
Configuration: Standard Battery Antenna: Fixed							
	CDMA 1900 E-Field						
Ch.	Backlight	Power	Dasy4 Reading	PMF	Peak Field	Category	
#		dBm	V/m		V/m	M	
25	ON	23.86	50.3	1.00	50.3	4	
600	ON	23.82	47.5	1.00	47.5	4	
1175	ON	23.96	43.1	1.00	43.1	4	
		CI	DMA 1900 H-Fi	eld			
Ch.	Backlight	Power	Dasy4 Reading	PMF	Peak Field	Category	
#	_	dBm	A/m		A/m	М	
25	ON	23.86	0.144	1.00	0.144	4	
600	ON	23.82	0.148	1.00	0.148	4	
1175	ON	23.96	0.112	1.00	0.112	4	



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10.4 Worst-Case Configuration Evaluation

The probe was rotated 360° at Azimuth axis in the worst case configuration. The rotation was performed at the location of maximum field strength in the included blocks.

CDMA 800 E-Field							
Configuratio	n:	Standard Battery		Antenna:	Fixed		
Ch.	Back	light	Conducted Power	Peak Field	PMF	Peak Field	Category
#			dBm	V/m		V/m	М
383	0	N	24.04	88.89	1.00	88.89	4

CDMA 1900 E-Field							
Configuratio	n:	Standard Battery		Antenna:	Fixed		
Ch.	Back	light	Conducted Power	Peak Field	PMF	Peak Field	Category
#			dBm	V/m		V/m	M
25	O	N	23.86	54.55	1.00	54.55	4

Data plots are shown in Appendix C



11 APPENDIX A: PROBE CALIBRATION CERTIFICATION

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S Schweizerischer Kalibrierdienst Service suisse d'étalonnage

C Service suisse d'étalonnage Servizio svizzero di taratura Swiss Calibration Service

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA

Multilateral Agreement for the recognition of calibration certificates

Client Kyocera U

Certificate No: ER3-2282 Aug09

Accreditation No.: SCS 108

CALIBRATION (CERTIFICAT	E	
Object	ER3DV6 - SN:2282		
Calibration procedure(s)	QA CAL-02.v5 and QA CAL-25.v2 Calibration procedure for E-field probes optimized for close near field evaluations in air		
Calibration date:	August 14, 200	9	
Condition of the calibrated item	In Tolerance		
		probability are given on the following pages a ory facility: environment temperature (22 ± 3)	
	TE critical for calibration)		
Calibration Equipment used (M&)	TE critical for calibration)	Cal Date (Certificate No.)	Scheduled Calibration
Calibration Equipment used (M&T			Scheduled Calibration Apr-10
Calibration Equipment used (M&) Primary Standards Power meter E4419B	ID#	Cal Date (Certificate No.)	
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A	ID# GB41293874	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030)	Apr-10
Calibration Equipment used (M&1 Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A	ID# GB41293874 MY41495277	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030)	Apr-10 Apr-10
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator	ID# GB41293874 MY41495277 MY41498087	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030)	Apr-10 Apr-10 Apr-10
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator	ID# GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b)	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027)	Apr-10 Apr-10 Apr-10 Mar-10
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 20 dB Attenuator Reference 70 dB Attenuator	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 20 dB Attenuator Reference 70 dB Attenuator	ID# GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b)	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: 2328 SN: 789	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8648C	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: 2328 SN: 789	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8648C	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5056 (20b) SN: S5129 (30b) SN: 2328 SN: 789	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator	ID# GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 789 ID# US3642U01700	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8548C Network Analyzer HP 8753E	ID# GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 789 ID# US3642U01700 US37390585	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09 In house check: Oct-09
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8548C Network Analyzer HP 8753E	ID# GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 789 ID# US3642U01700 US37390585 Name	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09 In house check: Oct-09
Calibration Equipment used (M&T Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8648C	ID# GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 789 ID# US3642U01700 US37390585 Name	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. ER3-2328_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09 In house check: Oct-09

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Calibration Laboratory of Schmid & Partner

Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





Schweizerischer Kalibrierdienst S Service suisse d'étalonnage C Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

			o: H3-6123_Jul09
CALIBRATION	CERTIFICAT	<u>E</u>	
Object	H3DV6 - SN:6123		
Calibration procedure(s)	QA CAL-03.v5 and QA CAL-25.v2 Calibration procedure for H-field probes optimized for close near field evaluations in air		
Calibration date:	July 16, 2009		
Condition of the calibrated item	In Tolerance		
The measurements and the unce	rtainties with confidence	tional standards, which realize the physical uniprobability are given on the following pages an ory facility: environment temperature $(22 \pm 3)^{\circ}$ C	d are part of the certificate.
Campiation Equipment used (Mid	i E chilcal for calibration)		
	V.	Cal Date (Certificate No.)	Scheduled Calibration
Primary Standards	ID # GB41293874	Cal Date (Certificate No.) 1-Apr-09 (No. 217-01030)	Scheduled Calibration Apr-10
Primary Standards Power meter E4419B	ID#		
Primary Standards Power meter E4419B Power sensor E4412A	ID # GB41293874	1-Apr-09 (No. 217-01030)	Apr-10
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A	ID# GB41293874 MY41495277	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030)	Apr-10 Apr-10
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator	ID # GB41293874 MY41495277 MY41498087	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030)	Apr-10 Apr-10 Apr-10
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c)	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026)	Apr-10 Apr-10 Apr-10 Mar-10
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b)	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe H3DV6	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b)	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference Probe H3DV6 DAE4 Secondary Standards	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 6182 SN: 789	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01028) 1-Dat-09 (No. 217-01027) 1-Oct-08 (No. H3-6182_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference Probe H3DV6 DAE4 Recondary Standards RF generator HP 8648C	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 6182 SN: 789 ID # US3642U01700	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01028) 1-Oct-08 (No. 217-01027) 1-Oct-08 (No. H3-6182_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference Probe H3DV6 DAE4 Secondary Standards RF generator HP 8648C	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 6182 SN: 789	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01028) 1-Dat-09 (No. 217-01027) 1-Oct-08 (No. H3-6182_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe H3DV6 DAE4 Secondary Standards RF generator HP 8648C Network Analyzer HP 8753E	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 6182 SN: 789 ID # US3642U01700 US37390585 Name	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. 217-01027) 1-Oct-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe H3DV6 DAE4 Secondary Standards RF generator HP 8648C Network Analyzer HP 8753E	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 6182 SN: 789 ID # US3642U01700 US37390585	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. 217-01027) 1-Oct-08 (No. H3-6182_Oct08) 19-Dec-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09 In house check: Oct-09
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe H3DV6 DAE4 Secondary Standards RF generator HP 8648C Network Analyzer HP 8753E Calibrated by:	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 6182 SN: 789 ID # US3642U01700 US37390585 Name	1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 1-Apr-09 (No. 217-01030) 31-Mar-09 (No. 217-01026) 31-Mar-09 (No. 217-01028) 31-Mar-09 (No. 217-01027) 1-Oct-08 (No. 217-01027) 1-Oct-08 (No. DAE4-789_Dec08) Check Date (in house) 4-Aug-99 (in house check Oct-07) 18-Oct-01 (in house check Oct-08)	Apr-10 Apr-10 Apr-10 Mar-10 Mar-10 Mar-10 Oct-09 Dec-09 Scheduled Check In house check: Oct-09 In house check: Oct-09

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Applicant:	Kyocera
FCC ID:	V65SCP-8600
Report #:	CT-8600-20RF-0510-R1

12 APPENDIX B: SYSTEM VALIDATION DATA PLOTS

(See attachment)

13 APPENDIX C: TEST RESULTS/PLOTS

(See attachment)

14 APPENDIX D: PHOTO TEST SETUP

(see attachment)